

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of

SAKAGUCHI et al.

Atty. Ref.: 4074-6

Serial No. To be assigned

Group: Unknown

Filed: July 11, 2003

Examiner: Unknown

For: SEMICONDUCTOR TESTING APPARATUS AND SEMICONDUCTOR TESTING METHOD

\* \* \* \* \*

July 11, 2003

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**INFORMATION DISCLOSURE STATEMENT**

As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the references listed on the attached form PTO-1449, a copy of each of which is enclosed. This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

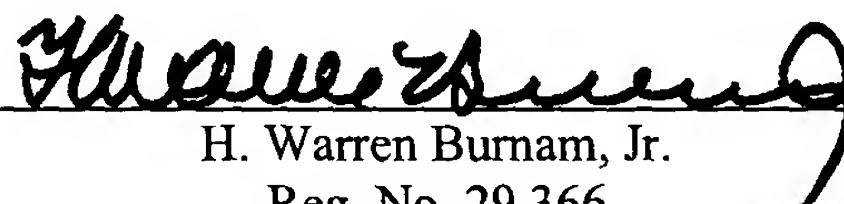
JP 2001-099899 is discussed on pages 4-5 of the specification.

The Examiner is requested to initial the attached form PTO-1449 and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

Respectfully submitted,

**NIXON & VANDERHYTE P.C.**

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